1x~3000000x Scanning Optical Microscope Digital Five Axis Motorized Stage A63.7081

Basic Information

Place of Origin: China
Brand Name: OPTO-EDU
Certification: CE, Rohs
Model Number: A63.7081
Minimum Order Quantity: 1 pc

Price: FOB \$1~1000, Depend on Order Quantity
 Packaging Details: Carton Packing, For Export Transportation

• Delivery Time: 5~20 Days

Payment Terms: T/T,West Union,Paypal
 Supply Ability: 5000 pcs/ Month



Product Specification

Resolution: Schottky Electron Gun

• Magnification: 1x~3000000x

• Electron Gun: Schottky Emission Electron Gun

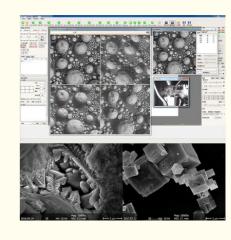
Accelerating Voltage: 0~30KVMax Specimen Diameter: 320mm

• Vacuum System: Ion Pump, Turbo Molecular Pump、Rotation

Pump, Getter Pum

• Highlight: 6x scanning optical microscope,

five axis scanning optical microscope



More Images





Opto-Edu (Beijing) Co., Ltd.





sale@optoedu.com



F-1501 Wanda Plaza, No. 18 Shijingshan Road, Beijing 100043, China

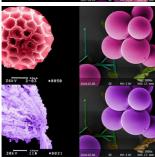




















Molybdenum Objective Apertures, Adjustable Outside Of Vacuu
 System, No Need Disassemble Objective To Change Aperture









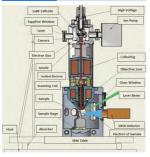


High voltage integrated commissioning
Brightness adjustment
Contrast adjustment
Magnification adjustment
Selected area scanning mode
Point scanning mode
Line scanning mode
Surface scanning
High voltage power monitoring

Automatic filament on / off
Electric to central adjustment
Objective lens adjustment
Objective degaussing
Electric rotation adjustment
Electron beam displacement adjustment
Electron beam tilt adjustment
Scanning speed adjustment
Swing centering

Potential shift regulation
Automatic brightness
Auto focus
Automatic astigmatism elimination
Management of microscope parameters
Real time display of scanning field size
Gun lens adjustment
Multichannel input
Ruler measurement

Vorking Principle



SEM	A63.7069 A63.7069-L A63.7069-LV		
Resolution	3nm@30KV(SE)	1.5nm@30KV(SE)	1.0nm@30KV(SE)
	6nm@30KV(BSE)	3nm@30KV(BSE)	3.0nm@1KV(SE)
			2.5nm@30KV(BSE)
Magnification	1x~450000x,Negative True	1x~600000x, Negative True Magnification	1x~3000000x Negative True Magnification
	Magnification		
Electron Gun	Pre-Centered Tungsten Filame	ent Schottky Field Emission Gun	Schottky Field Emission Gun
	Cartridge		
Voltage	Accelerating Voltage 0.2 30kV	, Continuous Adjustable, Adjust Step 100V@0-10Kv, 1	KV@10-30KV
Quick View	One Key Quick View Image Fu	unction N/A	N/A
Lens System	Three-levels Electromagnetic	Multi-levels Electromagnetic Tapered Lens	
	Tapered Lens		
Aperture	3 Molybdenum Objective Aper	tures, Adjustable Outside Of Vacuum System, No Nee	d Disassemble Objective To Change Aperture

Vacuum System	Turbo Molecular Pump Mechanical Pump Sample Room Vacuum>2.6E-3Pa Electron Gun Room Vacuum>2.6E-	1 Ion Pump Set 1 Turbo Molecular Pump 1 Mechanical Pump Sample Room Vacuum>6E-4Pa	Sputter Ion Pump Getter Ion Compound Pump Turbo Molecular Pump Mechanical Pump
	3Pa Fully Auto Vacuum Control Vacuum Interlock Function	Electron Gun Room Vacuum>2E-7 Pa Fully Auto Vacuum Control Vacuum Interlock Function	Sample Room Vacuum>6E-4Pa Electron Gun Room Vacuum>2E-7 Pa Fully Auto Vacuum Control Vacuum Interlock Function
	Optional Model: A63.7069-LV 1 Turbo Molecular Pump		
	2 Mechanical Pumps Sample Room Vacuum>2.6E-3Pa Electron Gun Room Vacuum>2.6E- 3Pa		
	Fully Auto Vacuum Control Vacuum Interlock Function		
	Low Vacuum Range 10~270Pa For Quick Switch in 90 Seconds For BSE(LV)		
Detector	SE: High Vacuum Secondary Electron Detector (With Detector Protection)	SE: High Vacuum Secondary Electron Detector (With Detector Protection)	SE: High Vacuum Secondary Electron Detector (With Detector Protection)
	BSE: Semiconductor 4 Segmentation Back Scattering Detector	Optional	Optional
	Optional Model: A63.7069-LV		
	BSE(LV): Semiconductor 4		
	Segmentation Back Scattering Detector		
	CCD: Infrared CCD Camera	CCD: Infrared CCD Camera	CCD: Infrared CCD Camera
xtend Port	2 Extend Ports On Sample Room	4 Extend Ports On Sample Room For	4 Extend Ports On Sample Room For
	For	BSE, EDS, BSD, WDS etc.	BSE, EDS, BSD, WDS etc.
· · · · · · · · · · · · · · · · · · ·	EDS, BSD, WDS etc.	E Avec Auto Middle Ctore	E Avec Auto Loure Stone
Specimen Stage	5 Axes Stage, 4 Auto +1 Manual Control	5 Axes Auto Middle Stage Travel Range:	5 Axes Auto Large Stage Travel Range:
, ago	Travel Range:	X=80mm, Y=50mm, Z=30mm,	X=150mm, Y=150mm, Z=60mm,
	X=70mm, Y=50mm, Z=45mm,	R=360°, T=-5°~+70°	R=360°, T=-5°~+70°
	R=360°, T=-5°~+90°(Manual) Touch Alert & Stop Function	Touch Alert & Stop Function	Touch Alert & Stop Function
	Optional Model:	Optional Model: A63.7080-L 5 Axes Auto Large Stage	
	A63.7069-L 5 Axes Auto Large Stage	0 0	
Max Specimen	Dia.175mm, Height 35mm	Dia.175mm, Height 20mm	Dia.340mm, Height 50mm
mage System	Real Still Image Max Resolution 4096x4096 Pixels, Image File Format: BMP(Default),	Real Still Image Max Resolution 16384x16384 Pixels, Image File Format: TIF(Default), BMP, GIF, JPG,	Real Still Image Max Resolution 16384x16384 Pixels, Image File Format: TIF(Default), BMP, GIF,
	GIF, JPG, PNG, TIF	PNG Video: Auto Record Digital .AVI Video	JPG, PNG Video: Auto Record Digital .AVI Video
Computer & Software		th Professional Image Analysis Software To Fully Con an Inter I5 3.2GHz, 4G Memory, 24" IPS LCD Monitor,	• •
		lous, Showing Real Time Magnification, Ruler, Voltage	·
Dimension & Weight	Microscope Body 800x800x1850mm Working Table 1340x850x740mm Total Weight 400Kg	n Microscope Body 800x800x1480mm Working Table 1340x850x740mm Total Weight 450Kg	Microscope Body 1000x1000x1730mm Working Table 1330x850x740mm Total Weight 550Kg
	Total Weight 4001/g	Total Wolghi Toury	Total Weight Soung
Optional	A50.7002 EDS Energy Dispersive X	- A50.7001 BSE Back Scattering Electron Detector	A50.7001 BSE Back Scattering Electron
Accessories	Ray Spectrometer	A50.7002 EDS Energy Dispersive X-Ray	Detector
	A50.7011 Ion Sputtering Coater	Spectrometer A50.7011 Ion Sputtering Coater	A50.7002 EDS Energy Dispersive X-Ray Spectrometer
		A50.7030 Motorize Control Panel	A50.7011 Ion Sputtering Coater A50.7030 Motorize Control Panel
Product Accessorie	es		
C.S.			







A50.7001	BSE Detector	Semiconductor Four Segment Back Scattering Detector; Available In Ingredients A+B, Morphology Info A-B; Available Sample Observe Without Sputtering Gold; Available In Observe Impurity And Distribution From Grayscale Map Directly.
A50.7002	EDS (X Ray Detector)	Silicon Nitride (Si3N4) Window To Optimize Low Energy X-ray Transmission For Light Element Analysis; Excellent Resolution And Their Advanced Low-noise Electronics Provide Outstanding Throughput Performance; The Small Footprint Offers Flexibility To Ensure Ideal Geometry And Aata Collection Conditions; The Detectors Contain A 30mm2 Chip.
A50.7003	EBSD (Electron Beam Backscattered Diffraction)	user could analysis crystal orientation, crystal phase and micro texture of materials and related materials performance,etc. automatic optimization of EBSD camera settings during the data collection, do interactive real-time analysis to obtain maximum information all the data were branded with time tag, which can be viewed at any time high resolution 1392 x 1040 x 12 Scanning and index speed: 198 points / sec, with Ni as the standard, under the condition of 2~5nA, it can ensure the index rate ≥99%; works well under the condition of low beam current and low voltage of 5kV at 100pA orientation measuring accuracy: Better than 0.1 degrees Using triplex index system: no need rely on single band definition , easy indexing of poor pattern quality dedicated database: EBSD special database obtained by electron diffraction: >400 phase structure Index ability: it can automatically index all crystal materials of 7 crystal systems. The advanced options include calculating elastic stiffness (Elastic Stiffness), Taylor (Taylor) factor, Schmidt (Schmid) factor and so on.
A50.7010	Coating Machine	Glass Protecting Shell: ∮ 250mm; 340mm High; Glass Processing Chamber: ∮ 88mm; 140mm High, ∮ 88mm; 57mm High; Specimen Stage Size: ∮ 40mm (max); Vacuum System:molecula Pump And Mechanical Pump; Vacuum Detection: Pirani Gage; Vacuum:better Than 2 X 10-3 Pa; Vacuum Protection:20 Pa With Microscale Inflation Valve; Specimen Movement: Plane Rotation,tilt Precession.
A50.7011	Ion Sputtering Coater	Glass Processing Chamber: ∮ 100mm; 130mm High; Specimen Stage Size: ∮ 40mm(Hold 6 Specimen Cups); Golden Target Size: ∮ 58mm*0.12mm(thickness); Vacuum Detection: Pirani Gage; Vacuum Protection:20 Pa With Microscale Inflation Valve; Medium Gas:argon Or Air With Argon Gas Special Air Inlet And Gas Regulating In Microscale.
A50.7012	Argon Ion Sputtering Coate	The Sample Was Plated With Carbon And Gold Under High Vacuum; Rotatable Sample Table, Uniform Coating, Particle Size About 3-5nm; No Selection Of Target Material, No Damage To Samples; The Functions Of Ion Cleaning And Ion Thinning Can Be Realized.
A50.7013	Critical Point Dryer	Inner Diameter: 82mm, Inner Length: 82mm; Pressure Range:0-2000psi; Temperature Range:0°-50° C (32°-122° F)
A50.7014	Electron Beam Lithography	Based On Scanning Electron Microscope, A Novel Nano-exposure System Was Developed; The Modificaton Has Kept All The Sem Functions For Making Nanoscale Line Width Image; The Modificated Ebl System Widly Applied Into Microelectronic Devices, Optoelectronic Devices, Quantun Devices, Microelectronics System R&d.
Real Effect		



R. Branch	AND THE THE PARTY OF THE PARTY		
	Aθ		
1	Field Emission Filam	ent Installed In Microscope	1 Pc
2	Sample Cup	Dia.13mm	3 Pcs
3	Sample Cup	Dia.32mm	5 Pcs
4	Carbon Double-sided Condu	uctive Tape 6mm	1 Pc

5	Vacuum Greas <mark>e</mark>	50g (Will not provide if ship by air)	1 Pc
6	Hairless Cloth		10pcs
7	Polishing Paste	(Will not provide if ship by air)	1 Pc
8	Sample Box		1 Pc
9	Cotton Swab	100pcs/Bag	2 Bags
10	Oil Mist Filter		1 Pc
	A63.7080, A		
1	Inner Hexagon Spa <mark>nner</mark>	1.5mm~10mm	1 Set
2	Tweezers	Length 100-120mm	1 Pc
3	Slotted Screwdriver	2*50mm, 2*125mm	2 Pcs
4	Cross Screwdriver	2*125mmm	1 Pc
5	Clean vent pipe	Dia.10/6.5mm(Out Diameter/Inner Diameter)	5m
6	Vent pressure reducing valve	Output Pressure 0-0.6MPa	1 Pc
7	Internal baking powe <mark>r supply</mark>	0-3A DC	2 Pcs

Working Condition, Requirement For Installation

Applications:
 SEM is mainly applied to the specimen surface appearance analysis. It is equipped with energy spectrum which is used for composition analysis and equipped with a small ion sputtering apparatus to help with sample surface treatment.

- 2 Power Supply Requirements:
 21 Voltage AC 220V ± 10%, 594 ± 11½, standard sine wave.
 22 Voltage AC 220V ± 10%, 594 ± 11½, standard sine wave.
 23 Is not recommended to share the power supply line with the instrument for equipment with high power and large power consumption charge.
 21 These power scalar meetad for.
 1 is Carman deciden microscope instrument body, computer, AC 220V, 504z, 16A.
 2 Michitachica power and arc compression AC 220V, 504z, 16A.

- 2. Moderated pump and as compressor AC 2009, 5014, 160

 2. Environmental Requirements for heritalisation (Bits)

 3.1 8 in sconmended to keep the energiation (Bits)

 3.1 8 in sconmended to keep the engine that (Sold Co.)

 3.1 8 in sconmended to keep the form of the sconmended to keep the sconmended to keep the sconmended to keep the sconmended to the sc

After-sale Service

OPTO-EDU







